## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination YOON ET AL. | Examiner | Art Unit | David L. Ometz | 2653 | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6772429	08-2004	Yoon et al	720/718
-	В	US-			
	С	US-	*		
	D	US-		13	
	Е	US-			
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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